I hereby certify that this corresponde deposited with the United States Posifirst class mail in an envelope address

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Kevin G. Rognew, Reg. No. 36,330

Date

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Applicants:

Louis A. Rigali et al.

Serial No:

09/829,305

Filed:

April 9, 2001

Group Art Unit: Examiner:

1763

LXGIII

Unknown

Title:

HIGH THROUGHPUT PLASMA TREATMENT SYSTEM

Atty Docket:

NOR-953B

Cincinnati, Ohio 45202

June 29, 2001

Assistant Commissioner for Patents Washington, DC 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with the duty of candor and good faith imposed by 37 C.F.R. §1.56 and means of complying therewith according to 37 C.F.R. §1.97 and 1.98, the references listed on the attached Form PTO-1449 are called to the attention of the Examiner in connection with the above-identified patent application.

The Examiner is urged to consider all of the cited documents and to make an independent evaluation of the teachings and materiality of each.

Applicants do not believe that any fees are due in connection with this submission. However, if such petition is due or any fees are necessary,

the Commissioner may consider this to be a request for such and charge any

ecessary fees to deposit account 23-3000.

Respectfully submitted,

WOOD, HERRON & EVANS, L.L.P.

Kevin G Rooney

Reg. No. \$6,330

2700 Carew Tower 441 Vine Street Cincinnati, OH 45202 (513) 241-2324 (voice) (513) 421-7269 (facsimile)

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	A.A	4	2	0	8	1	5	9	6/17/80	Uehara	et al.		414	225	225		
	A.B	4	2	5	2	5	9	5	2/24/81	Yamam	noto et al.		156	345			
	A.C	4	3	1	8	7	6	7	3/9/82	Hijikata	et al.		156	345			
	A.D	4	4	0	5	4	3	5	9/20/83	Tateish	i et al.		204	298			
	A.E	4	5	5	0	2	4	2	10/1985	Uehara	et al.		156	345			
	A.F	4	5	7	5	2	9	9	3/1986	Layton			414	222			
	A.G	4	5	8	4	0	4	5	4/1986	Richard	s		156	345			
	A.H	4	6	3	7	8	5	3	1/20/87	Bumble	et al.		156	345			
	A.I	4	7	0	5	4	4	4	11/1987	Tullis e	t al.		118	729X			
	A.J	4	8	1	6	1	1	6	3/1989	Davis			156	643			
	A.K	4 8 8 9 6 0 9 12/26/89								Canella			204	298			
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	B.A	5	0	4	4	8	7	1	9/1991	Davis	et al.		414	786		
	B.B	5	0	7	9	0	3	1	1/1992	Yama	zaki et al.		118	729X		
	B.C	5	1	1	6	6	4	0	5/1992	Mikan	mi et al.		118	719X		
	B.D	5	2	5	9	9	4	2	11/1993	Kemp	f		204	298.2	5	
	B.E	5	2	8	6	2	9	6	2/1994	Sato		-	118	719		
	B.F	5	2	8	8	6	8	4	2/1994	Yama	zaki et al.		118	723 E	х	
	B.G	5	2	9	2	3	9	3	3/1994	Mayda	an		156	345		
	В.Н	5	3	0	2	0	7	7	4/1994	Sato			414	609		
	B.I	5	3	0	3	6	7	1	4/19/94	Kondo	et al.		118	719		
	B.J	5	3	1	0	4	1	0	5/1994	Begin			29	25.01		
	B.K	5 3 1 4 2 9 8 5/1994 Kim								Kim			414	797.9		
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	C.A	5	3	8	7	2	6	5	2/1995	Kakizak	i et al.		118	730X	1	
	С.В	5	5	1	5	9	8	6	5/1996	Turlot e	et al.		156	345X		
	C.C	5	5	7	3	5	9	7	11/12/96	Lantsm	an		118	723MP		
	C.D	5	5	8	7	2	0	5	12/24/96	Saito et	al.		427	553		
	C.E	5	6	4	7	9	4	2	7/1997	Haji			156	281		
	C.F	5	7	6	7	0	0	8	6/1998	Haji			438	612		
	C.G	5	7	7	9	8	0	7	7/1998	Dornfes	t et al.		134	1.2	***	
	C.H	5	8	2	3	4	1	6	10/20/98	Haji			228	4.5	7/9/96	
	C.I	5	9	5	8	5	1	0	9/1991	Sivaram	akrishnam et al.		427	255.6		
	C.J	6	0	9	3	9	0	4	7/25/00	Haji			219	121.45	7/15/98	
	C.K															
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